

| | | | | | |
|-----------------------------------|--|--|---------------------------------------|---|-------------|
| Notice of References Cited | | | Application/Control No. 10/562,879 | Applicant(s)/Patent Under Reexamination OTAKE ET AL. | |
| | | | Examiner Jonathan D. Snelting | Art Unit 3652 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| * | A | US-2003/0200848 | 10-2003 | Kuchler, Fritz | 83/13 |
| * | B | US-2003/0049098 | 03-2003 | Parker et al. | 414/1 |
| * | C | US-4,837,734 | 06-1989 | Ichikawa et al. | 700/249 |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | JP 08282998 A (Abe, Tetsuo) 1996-10-29 (English machine translation of foreign publication already of record on applicant's IDS of 2005-12-29). [online] [retrieved 2009-09-02]. Retrieved from: http://dossier1.ipdl.inpit.go.jp/AIPN/odse_top_dn.ipdl?N0000=7400 |
| | V | JP 2000210824 A (Kiyuzaki et al.) 2000-08-02 (English machine translation of foreign publication already of record on applicant's IDS of 2005-12-29). [online] [retrieved 2009-09-02]. Retrieved from: http://dossier1.ipdl.inpit.go.jp/AIPN/odse_top_dn.ipdl?N0000=7400 |
| | W | JP 09210116 A (Ishihara et al.) 1997-08-12 (English machine translation of foreign publication already of record on applicant's IDS of 2005-12-29). [online] [retrieved 2009-09-02]. Retrieved from: http://dossier1.ipdl.inpit.go.jp/AIPN/odse_top_dn.ipdl?N0000=7400 |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.